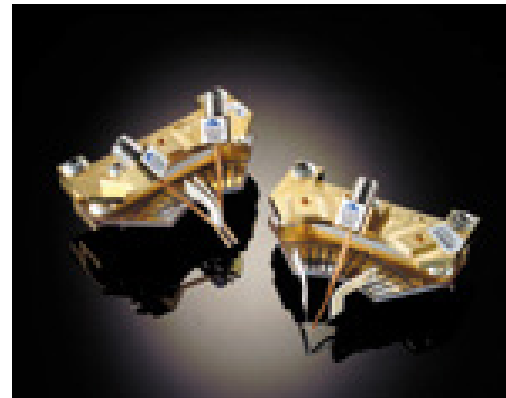
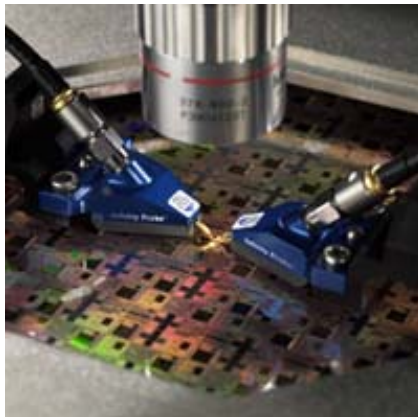
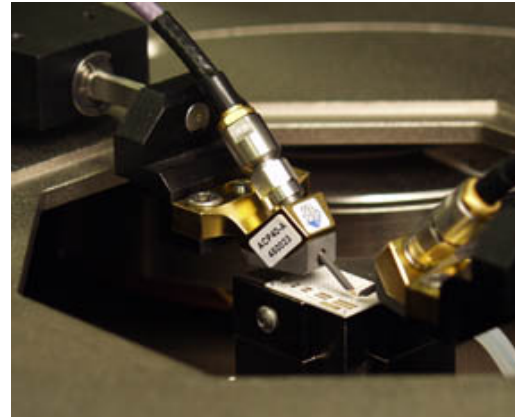
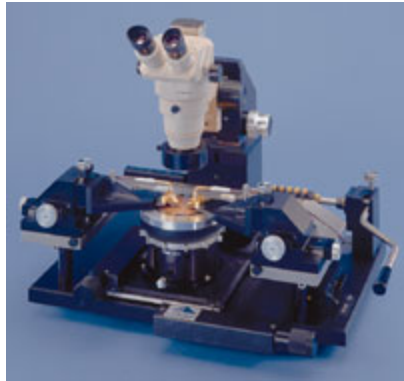


# ECE 451

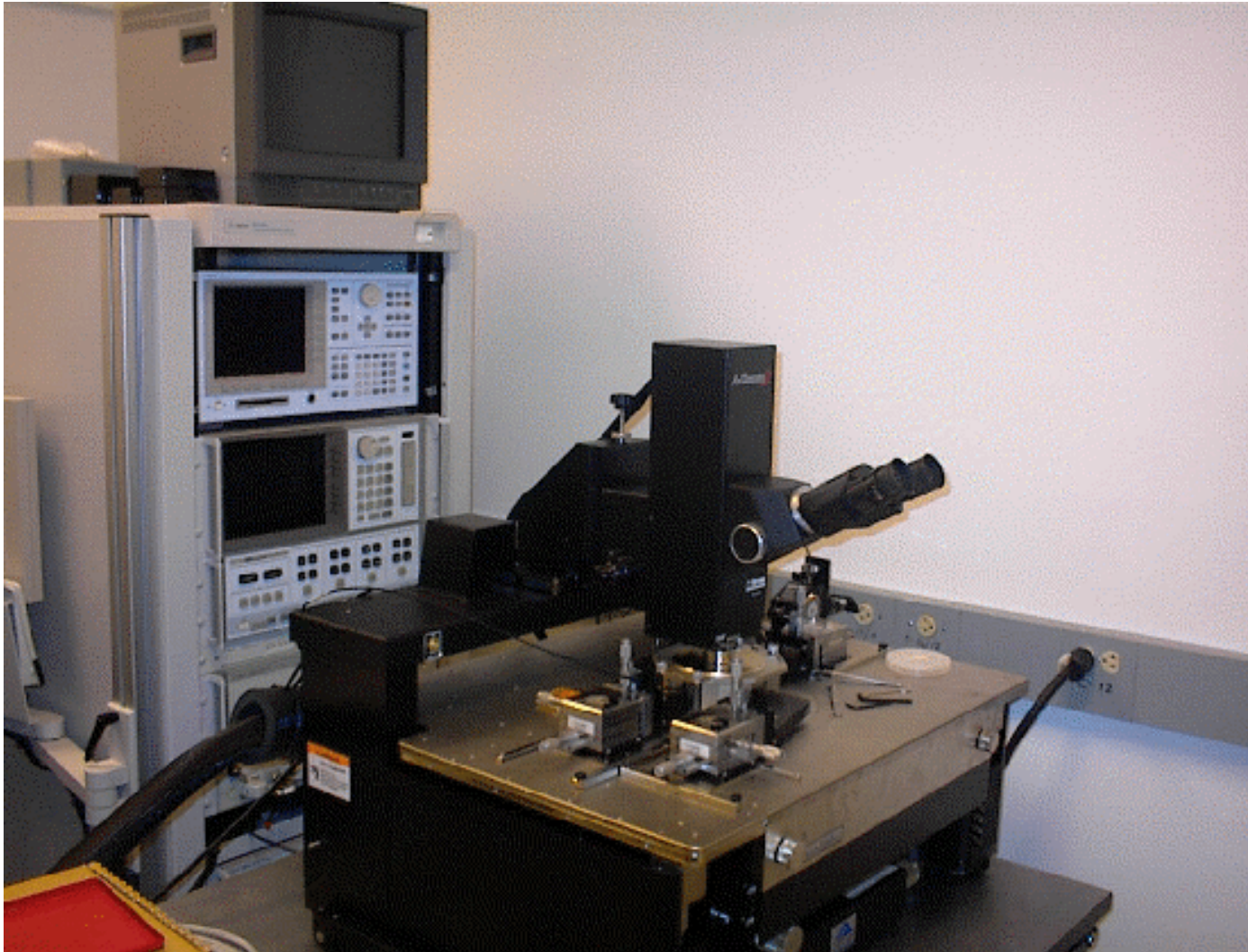
# On-Wafer Measurements

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# Probes & Probe Stations



# Probe Station & VNA



# Chip Probing

